



NSAI
Standards

Irish Standard
I.S. EN 62754:2017

Computation of waveform Parameter uncertainties

I.S. EN 62754:2017

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National Foreword

I.S. EN 62754:2017 is the adopted Irish version of the European Document EN 62754:2017, Computation of waveform Parameter uncertainties

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EUROPEAN STANDARD

EN 62754

NORME EUROPÉENNE

EUROPÄISCHE NORM

September 2017

ICS 17.220.20

English Version

Computation of waveform Parameter uncertainties (IEC 62754:2017)

Calcul des incertitudes des paramètres des formes d'onde
(IEC 62754:2017)

Berechnung der Messunsicherheiten von
Schwingungsabbildparametern
(IEC 62754:2017)

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EN 62754:2017

European foreword

The text of document 85/585/FDIS, future edition 1 of IEC 62754, prepared by IEC/TC 85 "Measuring equipment for electrical and electromagnetic quantities" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62754:2017.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2018-03-28
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In the official version, for Bibliography, the following notes have to be added for the standard indicated :

IEC 60359:2001

NOTE

Harmonized as EN 60359:2002.

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Annex ZA
(normative)

**Normative references to international publications
with their corresponding European publications**

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60469	2013	Transitions, pulses and related waveforms - Terms, definitions and algorithms	EN 60469	2013

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IEC 62754

Edition 1.0 2017-05

INTERNATIONAL STANDARD

NORME INTERNATIONALE



Computation of waveform parameter uncertainties

Calcul des incertitudes des paramètres des formes d'onde



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IEC 62754

Edition 1.0 2017-05

INTERNATIONAL STANDARD

NORME INTERNATIONALE



Computation of waveform parameter uncertainties

Calcul des incertitudes des paramètres des formes d'onde

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COMPUTATION OF WAVEFORM PARAMETER UNCERTAINTIES

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FDIS	Report on voting
85/585/FDIS	85/X588/RVD

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The terms used throughout this document which have been defined in Clause 3 are in italic type.

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COMPUTATION OF WAVEFORM PARAMETER UNCERTAINTIES

1 Scope

This document specifies methods for the computation of the temporal and amplitude parameters and their associated uncertainty for step-like and impulse-like waveforms. This document is applicable to any and all industries that generate, transmit, detect, receive, measure, and/or analyse these types of pulses.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60469:2013, *Transitions, pulses and related waveforms – Terms, definitions and algorithms*

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

3.1 aberration region

3.1.1 post-transition aberration region

interval between a user-specified *instant* and a fixed *instant*, where the fixed *instant* is the first sampling *instant* succeeding the 50 % *reference level instant* for which the corresponding *waveform* value is within the *state boundaries* of the *state* succeeding the 50 % *reference level instant*

[SOURCE: IEC 60469:2013, 3.2.1.1, modified – the note 1 to entry has been deleted.]

3.1.2 pre-transition aberration region

interval between a user-specified *instant* and a fixed *instant*, where the fixed *instant* is the first sampling *instant* preceding the 50 % *reference level instant* for which the corresponding *waveform* value is within the *state boundaries* of the *state* preceding the 50 % *reference level instant*

[SOURCE: IEC 60469:2013, 3.2.1.2, modified – the note 1 to entry has been deleted.]

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